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CY7C1061G/CY7C1061GE

16-Mbit (1M words × 16-bit) Static RAM with Error-Correcting Code (ECC)

Features

- High speed
 - $\Box t_{AA} = 10 \text{ ns}/15 \text{ ns}$
- Embedded error-correcting code (ECC) for single-bit error correction^[1, 2]
- Low active and standby currents
 - □ I_{CC} = 90 mA typical at 100 MHz
 - □ I_{SB2} = 20 mA typical
- Operating voltage range: 1.65 V to 2.2 V, 2.2 V to 3.6 V, and 4.5 V to 5.5 V
- 1.0 V data retention
- Transistor-transistor logic (TTL) compatible inputs and outputs
- Error indication (ERR) pin to indicate 1-bit error detection and correction
- Available in Pb-free 48-pin TSOP I, 54-pin TSOP II, and 48-ball VFBGA packages

Functional Description

CY7C1061G and CY7C1061GE are high-performance CMOS fast static RAM devices with embedded ECC^[1]. Both devices are offered in single and dual chip enable options and in multiple pin configurations. The CY7C1061GE device includes an ERR pin that signals a single-bit error-detection and correction event during a read cycle.

To access devices with a single chip enable input, assert the chip enable (CE) input LOW. To access dual chip enable devices, assert both chip enable inputs – CE₁ as LOW and CE₂ as HIGH.

To perform data writes, assert the Write Enable (WE) input LOW, and provide the data and address on the device data pins (I/On through I/O₁₅) and add<u>ress</u> pins (A₀ through A₁₉) respectively. The Byte High Enable (BHE) and Byte Low Enable (BLE) inputs control byte writes, and write data on the corresponding I/O lines to the memory location specified. BHE controls I/O₈ through I/O_{15} and \overline{BLE} controls I/O_0 through I/O_7 .

To perform data reads, assert the Output Enable (OE) input and provide the required address on the address lines. Read data is accessible on I/O lines (I/O₀ through I/O₁₅). You can perform byte accesses by asserting the required byte enable signal (BHE or BLE) to read either the upper byte or the lower byte of data from the specified address location.

All I/Os (I/O₀ through I/O₁₅) are placed in a high-impedance state when the device is deselected (CE HIGH for a single chip enable device and \overline{CE}_1 HIGH / CE_2 LOW for a dual chip enable device), or control signals are de-asserted (OE, BLE, BHE).

On the CY7C1061GE devices, the detection and correction of a single-bit error in the accessed location is indicated by the assertion of the ERR output (ERR = High). See the Truth Table on page 16 for a complete description of read and write modes.

The logic block diagrams are on page 2.

The CY7C1061G and CY7C1061GE devices are available in 48-pin TSOP I, 54-pin TSOP II, and 48-ball VFBGA packages.

For a complete list of related documentation, click here.

Product Portfolio

						Current Co	nsumption		
Product	Features and Options (see Pin Configurations on	Range	V _{CC} Range (V)	Speed	Operating	g I _{CC} , (mA)	Standby, I _{SB2} (mA)		
Floudet	page 4)	ixalige	(V)	(ns) 10/15		f = f _{max}		SB2 (IIIA)	
					Typ ^[3]	Max	Typ ^[3]	Max	
CY7C1061G18	Single or dual chip enables	Industrial	1.65 V-2.2 V	15	70	80	20	30	
CY7C1061G(E)30	Optional ERR pins		2.2 V-3.6 V	10	90	110			
CY7C1061G	Optional Extrapins		4.5 V–5.5 V	10	90	110			
	Address MSB A ₁₉ pin placement options compatible with Cypress and other vendors								

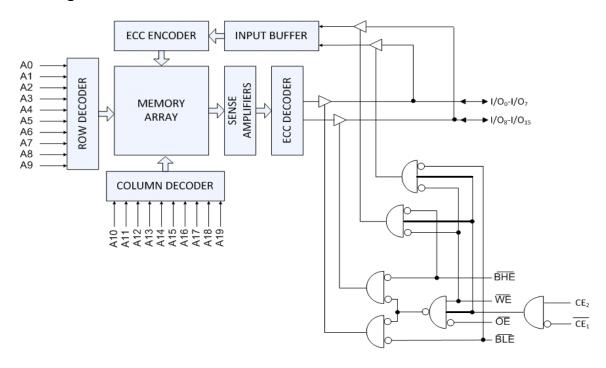
Notes

- This device does not support automatic write-back on error detection.
- SER FIT Rate < 0.1 FIT/Mb. Refer AN88889 for details.
- Typical values are included only for reference and are not guaranteed or tested. Typical values are measured at V_{CC} = 1.8 V (for a V_{CC} range of 1.65 V–2.2 V), V_{CC} = 3 V (for a V_{CC} range of 2.2 V–3.6 V), and V_{CC} = 5 V (for a V_{CC} range of 4.5 V–5.5 V), V_{CC} = 25 °C.

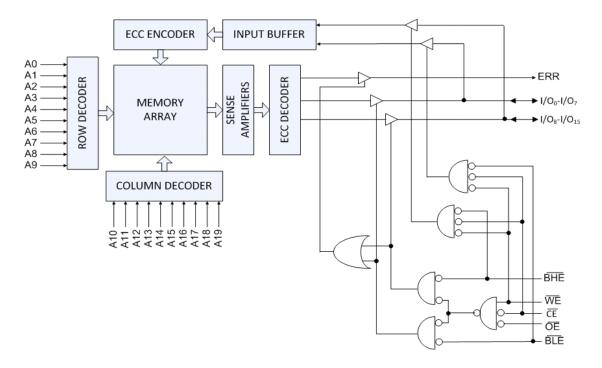
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Logic Block Diagram - CY7C1061G



Logic Block Diagram - CY7C1061GE



CY7C1061G/CY7C1061GE



Contents

Pin Configurations	4
Maximum Ratings	
Operating Range	7
DC Electrical Characteristics	
Capacitance	8
Thermal Resistance	
AC Test Loads and Waveforms	
Data Retention Characteristics	
Data Retention Waveform	
AC Switching Characteristics	
Switching Waveforms	
Truth Table	
ERR Output – CY7C1061GE	

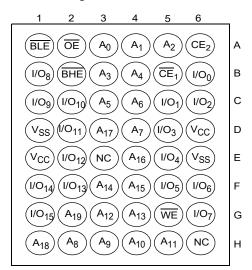
Ordering information	
Ordering Code Definitions	19
Package Diagrams	
Acronyms	23
Document Conventions	23
Units of Measure	23
Document History Page	24
Sales, Solutions, and Legal Information	25
Worldwide Sales and Design Support	25
Products	
PSoC® Solutions	25
Cypress Developer Community	25
Technical Support	



Pin Configurations

Figure 1. 48-ball VFBGA (6 × 8 × 1.0 mm) Pinout,
Dual Chip Enable without ERR, Address MSB A19 at Ball G2,
CY7C1061G^[4] Package/Grade ID: BVJXI

Figure 2. 48-ball VFBGA (6 × 8 × 1.0 mm) Pinout,
Dual Chip Enable without ERR, Address MSB A19 at Ball H6,
CY7C1061G^[4] Package/Grade ID: BVXI



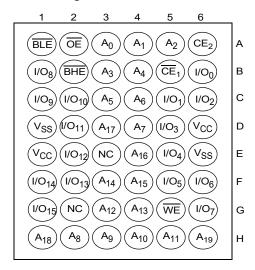
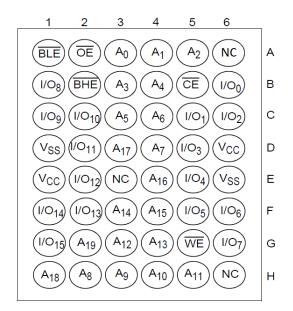


Figure 3. 48-ball VFBGA (6 × 8 × 1.0 mm) Pinout, Single Chip Enable without ERR, Address MSB A19 at Ball G2, CY7C1061G^[4]
Package/Grade ID: BV1XI



Note

^{4.} NC pins are not connected internally to the die.



Pin Configurations (continued)

Figure 4. 48-ball VFBGA (6 × 8 × 1.0 mm) Pinout, Single Chip Enable with ERR, Address MSB A19 at Ball G2, CY7C1061GE^[5, 6] Package/Grade ID: BV1XI

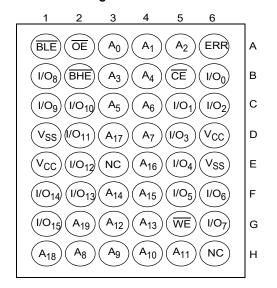


Figure 5. 48-ball VFBGA (6 × 8 × 1.0 mm) Pinout, Dual Chip Enable with ERR, Address MSB A19 at Ball G2, CY7C1061GE $^{[5,6]}$ Package/Grade ID: BVJXI

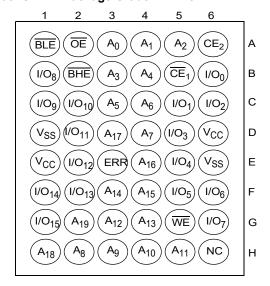
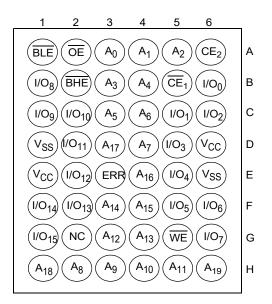


Figure 6. 48-ball VFBGA (6 × 8 × 1.0 mm) Pinout, Dual Chip Enable with ERR, Address MSB A19 at Ball H6, CY7C1061GE $^{[5,\,6]}$ Package/Grade ID: BVXI



- 5. NC pins are not connected internally to the die.
- 6. ERR is an Output pin. If not used, this pin should be left floating.



Pin Configurations (continued)

Figure 7. 48-pin TSOP I (12 × 18.4 × 1 mm) Pinout, Single Chip Enable with ERR, CY7C1061GE^[7, 8] Package/Grade ID: ZXI

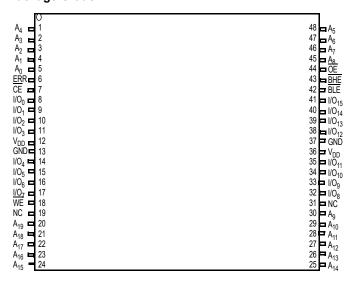


Figure 8. 48-pin TSOP I (12 × 18.4 × 1 mm) Pinout, Single Chip Enable without ERR, CY7C1061G^[7] Package/Grade ID: ZXI

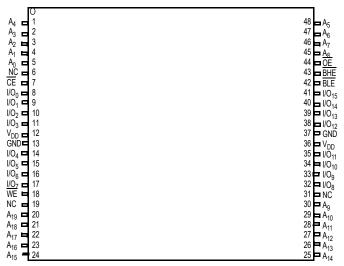


Figure 9. 54-pin TSOP II (22.4 × 11.84 × 1.0 mm) pinout, Dual Chip Enable without ERR, CY7C1061G^[7] Package/Grade ID: ZSXI

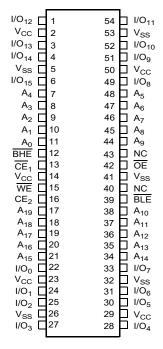


Figure 10. 54-pin TSOP II (22.4 × 11.84 × 1.0 mm) pinout, Dual Chip Enable with ERR, CY7C1061GE $^{[7,\ 8]}$ Package/Grade ID: ZSXI

I/O ₁₂	口	1	54		I/O ₁₁
V_{CC}	\Box	2	53	Ы	V_{SS}
I/O ₁₃	d	3	52	Ы	I/O ₁₀
I/O ₁₄	П.	4	51	Ы	I/O ₉
V_{SS}	d	5	50	Ы	V_{CC}
I/O ₁₅	d	6	49	Ы	I/O ₈
A_4	П	7	48	Ы	A ₅
A_3	d.	8	47	Ы	A_6
A_2	d	9	46	Ы	A ₇
A_1	d·	10	45	Ы	A ₈
A ₀	\Box	11	44	Ы	A ₉
BHE	d.	12	43	Ы	ERR
CE₁	\Box	13	42		OE
V_{CC}	\Box	14	41		V_{SS}
WE	\Box	15	40		NC
CE ₂	\Box	16	39		BLE
A ₁₉	\Box	17	38		A ₁₀
A ₁₈	_	18	37		A_{11}
A ₁₇	_	19	36		A ₁₂
A ₁₆	_	20	35		A ₁₃
A ₁₅	_	21	34		A ₁₄
I/O_0		22	33		I/O ₇
V_{CC}		23	32	Ш	V_{SS}
I/O ₁	_	24	31		I/O ₆
I/O_2		25	30	Ľ	I/O ₅
V_{SS}	_	26	29	H	V_{CC}
I/O ₃	4	27	28	Η	I/O_4

- 7. NC pins are not connected internally to the die.
- 8. ERR is an Output pin. If not used, this pin should be left floating.



Maximum Ratings

Exceeding maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Storage temperature-65 °C to +150 °C Ambient temperature with power applied55 °C to +125 °C Supply voltage

DC voltage applied to outputs in High Z State $^{[9]}$ –0.5 V to V $_{\rm CC}$ + 0.5 V

DC input voltage ^[9]	0.5 V to V _{CC} + 0.5 V
Current into outputs (LOW)	20 mA
Static discharge voltage (MIL-STD-883, Method 3015)	>2001 V
Latch-up current	> 140 mA

Operating Range

Grade	Ambient Temperature	V _{CC}
Industrial	–40 °C to +85 °C	1.65 V to 2.2 V, 2.2 V to 3.6 V, 4.5 V to 5.5 V

DC Electrical Characteristics

Over the operating range of -40 °C to 85 °C

D			To ak Oo w distance		10	11:4		
Parameter	Desc	ription	Test Conditions		Min	Typ [10]	Max	Unit
V _{OH}	Output	1.65 V to 2.2 V	V_{CC} = Min, I_{OH} = -0.1 mA		1.4	_	_	V
	HIGH voltage	2.2 V to 2.7 V	V_{CC} = Min, I_{OH} = -1.0 mA		2.0	_	_	•
		2.7 V to 3.0 V	$V_{\rm CC}$ = Min, $I_{\rm OH}$ = -4.0 mA		2.2	_	-	
		3.0 V to 3.6 V	V_{CC} = Min, I_{OH} = -4.0 mA		2.4	-	-	
		4.5 V to 5.5 V	$V_{\rm CC}$ = Min, $I_{\rm OH}$ = -4.0 mA		2.4	_	-	
		4.5 V to 5.5 V	V_{CC} = Min, I_{OH} = -0.1 mA		V _{CC} – 0.4 ^[11]	_	-	
V _{OL}		1.65 V to 2.2 V	V _{CC} = Min, I _{OL} = 0.1 mA		-	_	0.2	V
	voltage	2.2 V to 2.7 V	V _{CC} = Min, I _{OL} = 2 mA		-	_	0.4	
		2.7 V to 3.6 V	V _{CC} = Min, I _{OL} = 8 mA		-	_	0.4	
		4.5 V to 5.5 V	V _{CC} = Min, I _{OL} = 8 mA		-	_	0.4	
V _{IH} ^[9]	Input HIGH	1.65 V to 2.2 V			1.4	_	V _{CC} + 0.2	V
	voltage	2.2 V to 2.7 V			2.0	_	V _{CC} + 0.3]
		2.7 V to 3.6 V			2.0	_	V _{CC} + 0.3	
		4.5 V to 5.5 V			2.0	-	V _{CC} + 0.5	
V _{IL} ^[9]	Input LOW	1.65 V to 2.2 V			-0.2	_	0.4	V
	voltage	2.2 V to 2.7 V			-0.3	_	0.6	
		2.7 V to 3.6 V			-0.3	_	0.8	•
		4.5 V to 5.5 V			-0.5	_	0.8	
I _{IX}	Input leakage	e current	$GND \le V_{IN} \le V_{CC}$		-1.0	_	+1.0	μА
I _{OZ}	Output leaka	ge current	GND ≤ V _{OUT} ≤ V _{CC} , Outpu	ıt disabled	-1.0	_	+1.0	μА
I _{CC}	Operating su	pply current	V _{CC} = Max, I _{OUT} = 0 mA, CMOS levels	f = 100 MHz	-	90.0	110.0	mA
			CMOS levels	f = 66.7 MHz	-	70.0	80.0	
I _{SB1}	Automatic Cl current – TT	E power down L inputs	$ \begin{aligned} &\text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{IH}}^{ [12]}, \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{IH}} \text{ or V}_{\text{IN}} \leq \text{V}_{\text{IL}}, \text{f} = \text{f} \end{aligned} $	MAX	_	_	40.0	mA
I _{SB2}	Automatic Cl current – CM	E power down	$\begin{array}{l} \text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.2 \\ \text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.2 \text{ V or V}_{\text{IN}} \leq \end{array}$	V ^[12] , 0.2 V, f = 0	_	20.0	30.0	mA

Notes

Document Number: 001-81540 Rev. *T

^{9.} $V_{IL(min)}$ = -2.0 V and $V_{IH(max)}$ = V_{CC} + 2 V for pulse durations of less than 20 ns.

^{10.} Typical values are included only for reference and are not guaranteed or tested. Typical values are measured at V_{CC} = 1.8 V (for a V_{CC} range of 1.65 V–2.2 V),

V_{CC} = 3 V (for a V_{CC} range of 2.2 V-3.6 V), and V_{CC} range of 4.5 V-5.5 V), T_A = 25 °C.

11. This parameter is guaranteed by design and is not tested.

12. For all dual chip enable devices, CE is the logical combination of CE₁ and CE₂. When CE₁ is LOW and CE₂ is HIGH, CE is LOW; when CE₁ is HIGH or CE₂ is LOW, CE is HIGH.



Capacitance

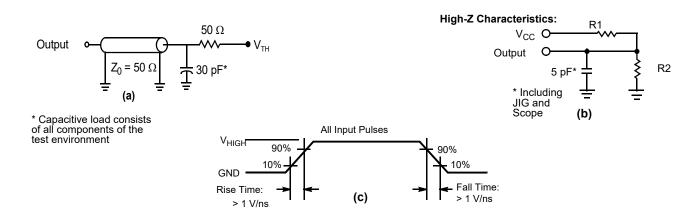
Parameter [13]	Description	Test Conditions	54-pin TSOP II	48-ball VFBGA	48-pin TSOP I	Unit
C _{IN}	Input capacitance	$T_A = 25 ^{\circ}\text{C}$, $f = 1 \text{MHz}$, $V_{CC} = V_{CC(typ)}$	10	10	10	pF
C _{OUT}	I/O capacitance		10	10	10	pF

Thermal Resistance

Parameter [13]	Description	Test Conditions	54-pin TSOP II	48-ball VFBGA	48-pin TSOP I	Unit
$\Theta_{\sf JA}$		Still air, soldered on a 3 × 4.5 inch, four-layer printed circuit board	93.63	31.50	57.99	°C/W
$\Theta_{\sf JC}$	Thermal resistance (junction to case)		21.58	15.75	13.42	°C/W

AC Test Loads and Waveforms

Figure 11. AC Test Loads and Waveforms^[14]



Parameters	1.8 V	3.0 V	5.0 V	Unit
R1	1667	317	317	Ω
R2	1538	351	351	Ω
V_{TH}	0.9	1.5	1.5	V
V _{HIGH}	1.8	3	3	V

^{13.} Tested initially and after any design or process changes that may affect these parameters.

^{14.} Full-device AC operation assumes a 100- μ s ramp time from 0 to V_{CC} (min) and 100- μ s wait time after V_{CC} stabilizes to its operational value.



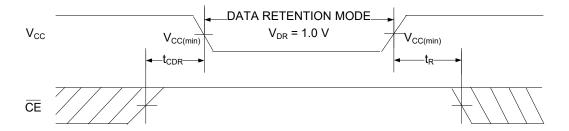
Data Retention Characteristics

Over the operating range of -40 °C to 85 °C

Parameter	Description	Conditions	Min	Max	Unit
V_{DR}	V _{CC} for data retention		1.0	_	V
I _{CCDR}	Data retention current	$V_{CC} = V_{DR}, \overline{CE} \ge V_{CC} - 0.2 V^{[15]}, V_{IN} \ge V_{CC} - 0.2 V \text{ or } V_{IN} \le 0.2 V$	-	30.0	mA
t _{CDR} ^[16]	Chip deselect to data retention time		0	_	ns
t _R ^[16, 17]	Operation recovery time	V _{CC} ≥ 2.2 V	10.0	_	ns
		V _{CC} < 2.2 V	15.0	_	ns

Data Retention Waveform

Figure 12. Data Retention Waveform [15]



T5. For all dual chip enable devices, $\overline{\text{CE}}$ is the logical combination of $\overline{\text{CE}}_1$ and $\overline{\text{CE}}_2$. When $\overline{\text{CE}}_1$ is LOW and $\overline{\text{CE}}_2$ is HIGH, $\overline{\text{CE}}$ is LOW; when $\overline{\text{CE}}_1$ is HIGH or $\overline{\text{CE}}_2$ is LOW, $\overline{\text{CE}}$ is HIGH.

^{16.} This parameter is guaranteed by design and is not tested

^{17.} Full-device operation requires linear V_{CC} ramp from V_{DR} to V_{CC} (min) \geq 100 μ s or stable at V_{CC} (min) \geq 100 μ s.



AC Switching Characteristics

Over the operating range of -40 °C to 85 °C

D ([18]	B	10	ns	15		
Parameter [18]	Description	Min	Max	Min	Max	Unit
Read Cycle		•	•	•		
t _{POWER}	V _{CC} (stable) to the first access ^[19, 20]	100.0	_	100.0	_	μs
t _{RC}	Read cycle time	10.0	_	15.0	_	ns
t _{AA}	Address to data / ERR valid	_	10.0	_	15.0	ns
t _{OHA}	Data / ERR hold from address change	3.0	-	3.0	_	ns
t _{ACE}	CE LOW to data / ERR valid [21]	_	10.0	_	15.0	ns
t _{DOE}	OE LOW to data / ERR valid	_	5.0	_	8.0	ns
t _{LZOE}	OE LOW to low Z [22, 23, 24]	0	_	1.0	_	ns
t _{HZOE}	OE HIGH to high Z [22, 23, 24]	_	5.0	_	8.0	ns
t _{LZCE}	CE LOW to low Z [21, 22, 23, 24]	3.0	_	3.0	_	ns
t _{HZCE}	CE HIGH to high Z [21, 22, 23, 24]	_	5.0	_	8.0	ns
t _{PU}	CE LOW to power-up [20, 21]	0	_	0	_	ns
t _{PD}	CE HIGH to power-down [20, 21]	_	10.0	_	15.0	ns
t _{DBE}	Byte enable to data valid	_	5.0	_	8.0	ns
t _{LZBE}	Byte enable to low Z ^[22, 23]	0	_	1.0	_	ns
t _{HZBE}	Byte disable to high Z ^[22, 23]	_	6.0	_	8.0	ns
Write Cycle [2	5, 26]					
t _{WC}	Write cycle time	10.0	_	15.0	_	ns
t _{SCE}	CE LOW to write end [21]	7.0	_	12.0	_	ns
t _{AW}	Address setup to write end	7.0	_	12.0	_	ns
t _{HA}	Address hold from write end	0	_	0	_	ns
t _{SA}	Address setup to write start	0	_	0	_	ns
t _{PWE}	WE pulse width	7.0	_	12.0	_	ns
t _{SD}	Data setup to write end	5.0	_	8.0	_	ns
t _{HD}	Data hold from write end	0	_	0	_	ns
t _{LZWE}	WE HIGH to low Z [22, 23, 24]	3.0	_	3.0	_	ns
t _{HZWE}	WE LOW to high Z [22, 23, 24]	_	5.0	_	8.0	ns
t _{BW}	Byte Enable to write end	7.0	_	12.0	_	ns

^{18.} Test conditions assume signal transition time (rise/fall) of 3 ns or less, timing reference levels of 1.5 V (for $V_{CC} \ge 3$ V) and $V_{CC}/2$ (for $V_{CC} < 3$ V), and input pulse levels of 0 to 3 V (for $V_{CC} \ge 3$ V) and 0 to V_{CC} (for $V_{CC} < 3$ V). Test conditions for the read cycle use the output loading, shown in part (a) of Figure 11 on page 8, unless specified

^{19.} t_{POWER} gives the minimum amount of time that the power supply is at stable V_{CC} until the first memory access is performed.

^{20.} These parameters are guaranteed by design and are not tested.

^{21.} For all dual chip enable devices, $\overline{\text{CE}}$ is the logical combination of $\overline{\text{CE}}_1$ and $\overline{\text{CE}}_2$. When $\overline{\text{CE}}_1$ is LOW and $\overline{\text{CE}}_2$ is HIGH, $\overline{\text{CE}}$ is LOW; when $\overline{\text{CE}}_1$ is HIGH or $\overline{\text{CE}}_2$ is LOW,

 $^{22.\} t_{HZOE}, t_{HZCE}, t_{HZWE}, \text{and } t_{HZBE} \text{ are specified with a load capacitance of 5 pF, as shown in part (b) of Figure 11 on page 8.} \ Hi-Z, Lo-Z \ transition is measured \pm 200 \ mV \ from steady state$ voltage.

^{23.} At any temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZBE} is less than t_{LZBE}, t_{HZOE} is less than t_{LZDE}, and t_{HZWE} is less than t_{LZWE} for any device.

^{24.} Tested initially and after any design or process changes that may affect these parameters.

25. The internal write time of the memory is defined by the overlap of WE = V_{IL}, CE = V_{IL}, and BHE or BLE = V_{IL}. These signals must be LOW to initiate a write, and the HIGH transition of any of these signals can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates

^{26.} The minimum write pulse width for Write Cycle No. 2 ($\overline{\text{WE}}$ Controlled, $\overline{\text{OE}}$ LOW) should be sum of t_{HZWE} and t_{SD} .



Switching Waveforms

Figure 13. Read Cycle No. 1 of CY7C1061G (Address Transition Controlled) [27, 28]

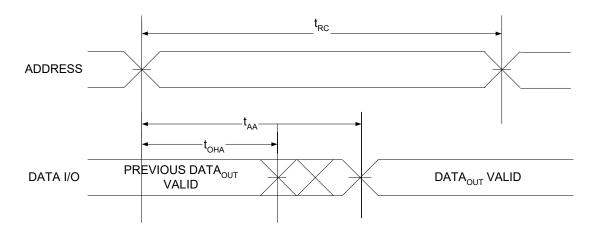
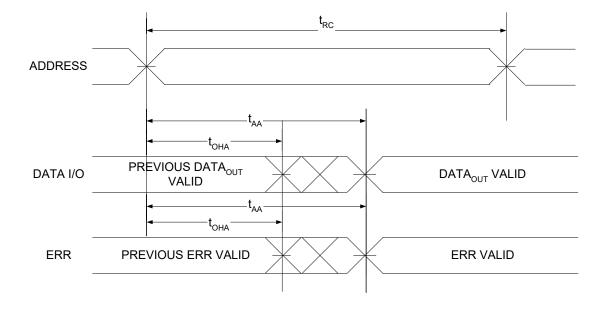


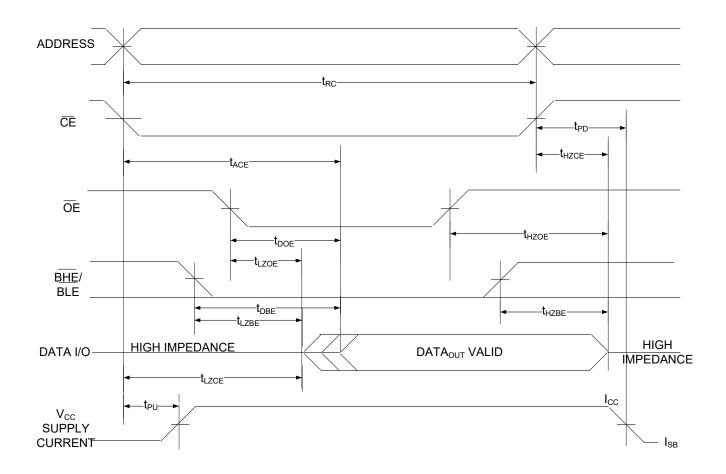
Figure 14. Read Cycle No. 2 of CY7C1061GE (Address Transition Controlled) [27, 28]



Notes 27. The device is continuously selected, $\overline{OE} = V_{IL}$, $\overline{CE} = V_{IL}$, \overline{BHE} or \overline{BLE} or both = V_{IL} . 28. \overline{WE} is HIGH for read cycle.



Figure 15. Read Cycle No. 3 (OE Controlled) [29, 30, 31]



^{29.} For all dual chip enable devices, \overline{CE} is the logical combination of \overline{CE}_1 and \overline{CE}_2 . When \overline{CE}_1 is LOW and \overline{CE}_2 is HIGH, \overline{CE} is LOW; when \overline{CE}_1 is HIGH or \overline{CE}_2 is LOW, \overline{CE} is HIGH.

^{30.} WE is HIGH for read cycle.
31. Address valid prior to or coincident with $\overline{\text{CE}}$ LOW transition.



Figure 16. Write Cycle No. 1 ($\overline{\text{CE}}$ Controlled) $^{[32,\,33,\,34]}$

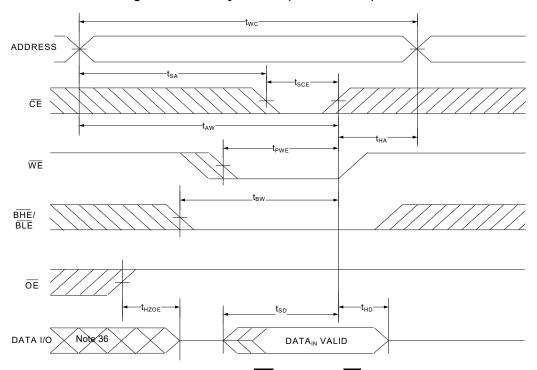
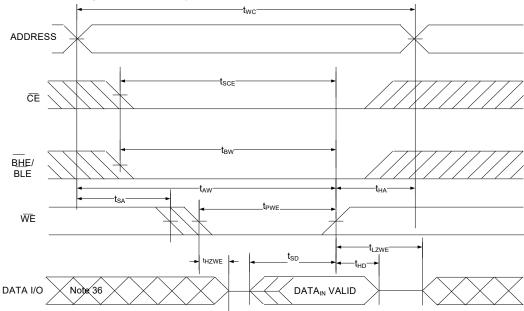


Figure 17. Write Cycle No. 2 (WE Controlled, $\overline{\text{OE}}$ LOW) $^{[32,\ 33,\ 34,\ 35]}$



- 32. For all dual chip enable devices, $\overline{\text{CE}}$ is the logical combination of $\overline{\text{CE}}_1$ and $\overline{\text{CE}}_2$. When $\overline{\text{CE}}_1$ is LOW and $\overline{\text{CE}}_2$ is HIGH, $\overline{\text{CE}}$ is LOW; when $\overline{\text{CE}}_1$ is HIGH or $\overline{\text{CE}}_2$ is LOW, $\overline{\text{CE}}_1$ is HIGH.
- 33. The internal write time of the memory is defined by the overlap of WE = V_{IL}, \overlap cE = V_{IL} and \overlap bHE or \overlap EE = V_{IL}. These signals must be LOW to initiate a write, and the HIGH transition of any of these signals can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates the write.
- 34. Data I/O is in high-impedance state if $\overline{CE} = V_{IH}$, or $\overline{OE} = V_{IH}$ or \overline{BHE} , and/or $\overline{BLE} = V_{IH}$.

 35. The minimum write cycle pulse width should be equal to sum of t_{HZWE} and t_{SD} .
- 36. During this period the I/Os are in output state. Do not apply input signals.



ADDRESS BHE/BLE t_{HZOE} DATA_{IN} VALID

Figure 18. Write Cycle No. 3 (WE Controlled) [37, 38, 39]

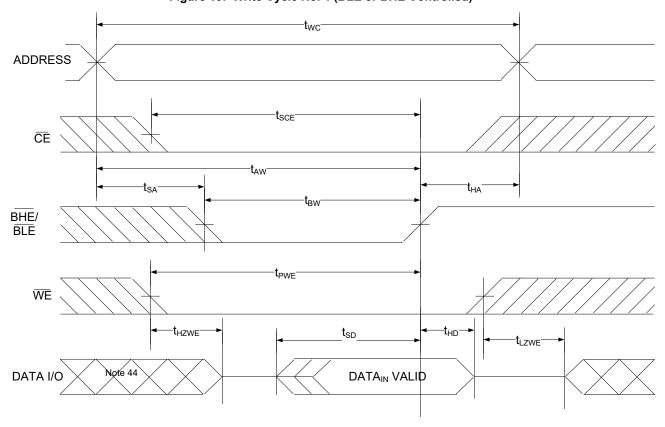
^{37.} For all dual chip enable devices, \overline{CE} is the logical combination of \overline{CE}_1 and \overline{CE}_2 . When \overline{CE}_1 is LOW and \overline{CE}_2 is HIGH, \overline{CE} is LOW; when \overline{CE}_1 is HIGH or \overline{CE}_2 is LOW, \overline{CE} is HIGH.

^{38.} The internal write time of the memory is defined by the overlap of WE = V_{IL}, CE = V_{IL} and BHE or BLE = V_{IL}. These signals must be LOW to initiate a write, and the HIGH transition of any of these signals can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates

^{39.} Data I/O is in high-impedance state if $\overline{CE} = V_{IH}$, or $\overline{OE} = V_{IH}$ or \overline{BHE} , and/or $\overline{BLE} = V_{IH}$. 40. During this period, the I/Os are in output state. Do not apply input signals.



Figure 19. Write Cycle No. 4 (BLE or BHE Controlled) [41, 42, 43]



^{41.} For all dual chip enable devices, \overline{CE} is the logical combination of \overline{CE}_1 and \overline{CE}_2 . When \overline{CE}_1 is LOW and \overline{CE}_2 is HIGH, \overline{CE} is LOW; when \overline{CE}_1 is HIGH or \overline{CE}_2 is LOW, \overline{CE} is HIGH.

^{42.} The internal write time of the memory is defined by the overlap of WE = V_{IL}, $\overline{\text{CE}} = \text{V}_{\text{IL}}$ and $\overline{\text{BHE}}$ or $\overline{\text{BLE}} = \text{V}_{\text{IL}}$. These signals must be LOW to initiate a write, and the HIGH transition of any of these signals can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates

^{43.} Data I/O is in high-impedance state if $\overline{CE} = V_{IH}$, or $\overline{OE} = V_{IH}$ or \overline{BHE} , and/or $\overline{BLE} = V_{IH}$.

^{44.} During this period, the I/Os are in output state. Do not apply input signals.



Truth Table

CE [45]	OE	WE	BLE	BHE	I/O ₀ –I/O ₇	I/O ₈ -I/O ₁₅	Mode	Power
Н	X ^[46]	X ^[46]	X ^[46]	X ^[46]	High-Z	High-Z	Power down	Standby (I _{SB})
L	L	Н	L	L	Data out	Data out	Read all bits	Active (I _{CC})
L	L	Н	L	Н	Data out	High-Z	Read lower bits only	Active (I _{CC})
L	L	Н	Н	L	High-Z	Data out	out Read upper bits only Active (I _{CC})	
L	Х	L	L	L	Data in	Data in	ata in Write all bits Active (I _{CC})	
L	Х	L	L	Н	Data in	High-Z	ligh-Z Write lower bits only Active (I _{CC})	
L	Х	L	Н	L	High-Z	Data in	Mrite upper bits only Active (I _{CC})	
L	Н	Н	Χ	Х	High-Z	High-Z	Selected, outputs disabled Active (I _{CC})	
L	Х	Х	Ι	Н	High-Z	High-Z	Selected, outputs disabled Active (I _{CC})	

ERR Output - CY7C1061GE

Output [47]	Mode	
0 Read operation, no single-bit error in the stored data.		
1 Read operation, single-bit error detected and corrected.		
High-Z	Device deselected or outputs disabled or Write operation	

^{45.} For all dual chip enable devices, \overline{CE} is the logical combination of \overline{CE}_1 and \overline{CE}_2 . When \overline{CE}_1 is LOW and \overline{CE}_2 is HIGH, \overline{CE} is LOW; when \overline{CE}_1 is HIGH or \overline{CE}_2 is LOW, \overline{CE} is HIGH.

^{46.} The input voltage levels on these pins should be either at V_{IH} or V_{IL} . 47. ERR is an Output pin. If not used, this pin should be left floating.



Ordering Information

Speed (ns)	Voltage Range	Ordering Code	Package Diagram	Package Type (all Pb-free)	Key Features / Differentiators	ERR Pin / Ball	Operating Range
10	4.5 V–5.5 V	CY7C1061G-10BV1XI	51-85150	48-ball VFBGA	Single Chip Enable,	No	Industrial
		CY7C1061GE-10BV1XI			Address MSB A19 at ball G2	Yes	
		CY7C1061G-10BVJXI			Dual Chip Enable,	No	
		CY7C1061GE-10BVJXI			Address MSB A19 at ball G2	Yes	
		CY7C1061G-10BVXI			Dual Chip Enable,	No	
		CY7C1061GE-10BVXI			Address MSB A19 at ball H6	Yes	
		CY7C1061G-10ZSXI	51-85160	54-pin TSOP II	Dual Chip Enable	No	
		CY7C1061GE-10ZSXI				Yes	
		CY7C1061G-10ZXI	51-85183	48-pin TSOP I	Single Chip Enable	No	
		CY7C1061GE-10ZXI				Yes	
	2.2 V-3.6 V	CY7C1061G30-10BV1XI	51-85150	48-ball VFBGA		No	
		CY7C1061GE30-10BV1XI			Address MSB A19 at ball G2	Yes	
		CY7C1061G30-10BVJXI			Dual Chip Enable,	No	
		CY7C1061GE30-10BVJXI			Address MSB A19 at ball G2	Yes	- -
		CY7C1061G30-10BVXI			Dual Chip Enable,	No	
		CY7C1061GE30-10BVXI			Address MSB A19 at ball H6	Yes	
		CY7C1061G30-10ZSXI	51-85160	54-pin TSOP II	Dual Chip Enable	No	
		CY7C1061GE30-10ZSXI				Yes	
		CY7C1061G30-10ZXI	51-85183	48-pin TSOP I	Single Chip Enable	No	
		CY7C1061GE30-10ZXI				Yes	
15	1.65 V-2.2 V	CY7C1061GE18-15BV1XI	51-85150	48-ball VFBGA	Single Chip Enable,	Yes	
		CY7C1061G18-15BV1XI			Address MSB A19 at ball G2	No	
		CY7C1061GE18-15BVJXI			Dual Chip Enable,	Yes	1
		CY7C1061G18-15BVJXI			Address MSB A19 at ball G2	No	
		CY7C1061GE18-15BVXI			Dual Chip Enable,	Yes	
		CY7C1061G18-15BVXI			Address MSB A19 at ball H6	No	
		CY7C1061GE18-15ZSXI	51-85160	54-pin TSOP II	Dual Chip Enable	Yes	
		CY7C1061G18-15ZSXI				No	
		CY7C1061GE18-15ZXI	51-85183	48-pin TSOP I	Single Chip Enable	Yes	
		CY7C1061G18-15ZXI]			No	

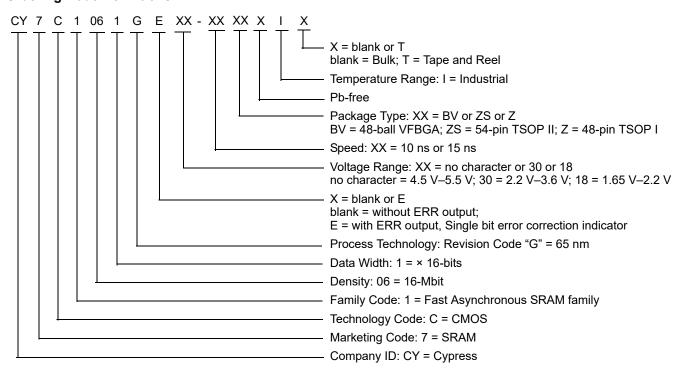


Ordering Information (continued)

Speed (ns)	Voltage Range	Ordering Code	Package Diagram	Package Type (all Pb-free)	Key Features / Differentiators	ERR Pin / Ball	Operating Range
10 4.5	4.5 V-5.5 V	CY7C1061G-10BV1XIT	51-85150	48-ball VFBGA	Single Chip Enable,	No	Industrial
		CY7C1061GE-10BV1XIT			Address MSB A19 at ball G2, Tape and Reel	Yes	
		CY7C1061G-10BVJXIT			Dual Chip Enable,	No	
		CY7C1061GE-10BVJXIT			Address MSB A19 at ball G2, Tape and Reel	Yes	
		CY7C1061G-10BVXIT			Dual Chip Enable,	No	
		CY7C1061GE-10BVXIT			Address MSB A19 at ball H6, Tape and Reel	Yes	
		CY7C1061G-10ZSXIT	51-85160	54-pin TSOP II	Dual Chip Enable,	No	
		CY7C1061GE-10ZSXIT		•	Tape and Reel	Yes	
		CY7C1061G-10ZXIT	51-85183	48-pin TSOP I	Single Chip Enable,	No	
		CY7C1061GE-10ZXIT			Tape and Reel	Yes	
	2.2 V-3.6 V	CY7C1061G30-10BV1XIT	51-85150	48-ball VFBGA	Single Chip Enable,	No	
		CY7C1061GE30-10BV1XIT			Address MSB A19 at ball G2, Tape and Reel	Yes	
		CY7C1061G30-10BVJXIT			Dual Chip Enable,	No	
		CY7C1061GE30-10BVJXIT			Address MSB A19 at ball G2, Tape and Reel	Yes	
		CY7C1061G30-10BVXIT			Dual Chip Enable,	No	
		CY7C1061GE30-10BVXIT			Address MSB A19 at ball H6, Tape and Reel	Yes	
		CY7C1061G30-10ZSXIT	51-85160	54-pin TSOP II	Dual Chip Enable,	No	
		CY7C1061GE30-10ZSXIT			Tape and Reel	Yes	
		CY7C1061G30-10ZXIT	51-85183	48-pin TSOP I	Single Chip Enable,	No	1
		CY7C1061GE30-10ZXIT			Tape and Reel	Yes	
15	1.65 V-2.2 V	CY7C1061GE18-15BV1XIT	51-85150	48-ball VFBGA	Single Chip Enable,	Yes	
		CY7C1061G18-15BV1XIT			Address MSB A19 at ball G2, Tape and Reel	No	
		CY7C1061GE18-15BVJXIT			Dual Chip Enable,	Yes	
		CY7C1061G18-15BVJXIT			Address MSB A19 at ball G2, Tape and Reel	No	
		CY7C1061GE18-15BVXIT			Dual Chip Enable,	Yes	
		CY7C1061G18-15BVXIT			Address MSB A19 at ball H6, Tape and Reel	No	
		CY7C1061GE18-15ZSXIT	51-85160	54-pin TSOP II	Dual Chip Enable,	Yes	
		CY7C1061G18-15ZSXIT			Tape and Reel	No	
		CY7C1061GE18-15ZXIT	51-85183	48-pin TSOP I	Single Chip Enable,	Yes	
		CY7C1061G18-15ZXIT	1		Tape and Reel	No	1



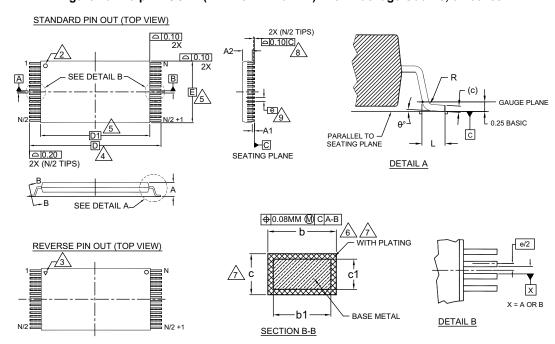
Ordering Code Definitions





Package Diagrams

Figure 20. 48-pin TSOP I (12 × 18.4 × 1.0 mm) Z48A Package Outline, 51-85183



SYMBOL	DIMENSIONS				
STIVIBOL	MIN.	NOM.	MAX.		
Α	-	-	1.20		
A1	0.05	1	0.15		
A2	0.95	1.00	1.05		
b1	0.17	0.20	0.23		
b	0.17	0.22	0.27		
c1	0.10	_	0.16		
С	0.10		0.21		
D	20.00 BASIC				
D1	18.40 BASIC				
E	12.00 BASIC				
е	0.50 BASIC				
L	0.50	0.60	0.70		
θ	0°	_	8		
R	0.08	_	0.20		
N	48				

NOTES:

1. DIMENSIONS ARE IN MILLIMETERS (mm).

2. PIN 1 IDENTIFIER FOR STANDARD PIN OUT (DIE UP).

PIN 1 IDENTIFIER FOR REVERSE PIN OUT (DIE DOWN): INK OR LASER MARK.

TO BE DETERMINED AT THE SEATING PLANE [-C]. THE SEATING PLANE IS
DEFINED AS THE PLANE OF CONTACT THAT IS MADE WHEN THE PACKAGE

LEADS ARE ALLOWED TO REST FREELY ON A FLAT HORIZONTAL SURFACE.

A DIMENSIONS D1 AND E DO NOT INCLUDE MOLD PROTRUSION, ALLOWABLE

DIMENSIONS D1 AND E DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE MOLD PROTRUSION ON E IS 0.15mm PER SIDE AND ON D1 IS 0.25mm PER SIDE.

DIMENSION 6 DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08mm TOTAL IN EXCESS OF 6 DIMENSION AT MAX. MATERIAL CONDITION. DAMBAR CANNOT BE LOCATED ON LOWER RADIUS OR THE FOOT. MINIMUM SPACE BETWEEN PROTRUSION AND AN ADJACENT LEAD TO BE 0.07mm.

THESE DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.10mm AND 0.25mm FROM THE LEAD TIP.

LEAD COPLANARITY SHALL BE WITHIN 0.10mm AS MEASURED FROM THE SEATING PLANE.

DIMENSION "e" IS MEASURED AT THE CENTERLINE OF THE LEADS.

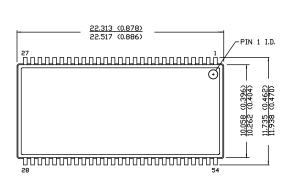
10. JEDEC SPECIFICATION NO. REF: MO-142(D)DD.

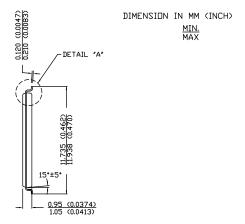
51-85183 *F

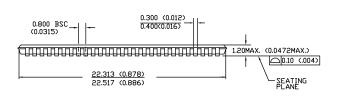


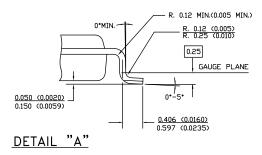
Package Diagrams (continued)

Figure 21. 54-pin TSOP II (22.4 × 11.84 × 1.0 mm) Z54-II Package Outline, 51-85160







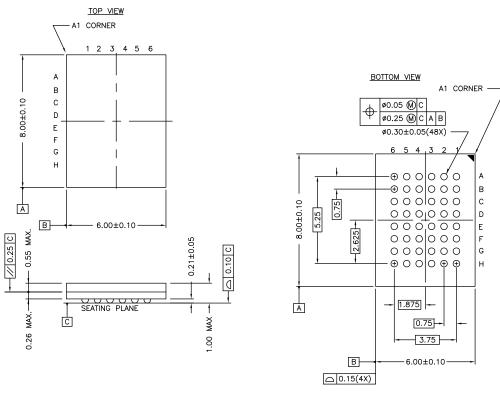


51-85160 *E



Package Diagrams (continued)

Figure 22. 48-ball VFBGA (6 × 8 × 1.0 mm) BV48/BZ48 Package Outline, 51-85150



NOTE:
PACKAGE WEIGHT: See Cypress Package Material Declaration Datasheet (PMDD)
posted on the Cypress web.

51-85150 *H



Acronyms

Acronym	Description			
BHE	Byte High Enable			
BLE	Byte Low Enable			
CE	Chip Enable			
CMOS	Complementary Metal Oxide Semiconductor			
I/O	Input/Output			
ŌĒ	Output Enable			
SRAM	Static Random Access Memory			
TSOP	Thin Small Outline Package			
TTL	Transistor-Transistor Logic			
VFBGA	Very Fine-Pitch Ball Grid Array			
WE	Write Enable			

Document Conventions

Units of Measure

Symbol	Unit of Measure			
°C	degree Celsius			
MHz	megahertz			
μΑ	microampere			
μS	microsecond			
mA	milliampere			
mm	millimeter			
ns	nanosecond			
Ω	ohm			
%	percent			
pF	picofarad			
V	volt			
W	watt			



Document History Page

	Document Title: CY7C1061G/CY7C1061GE, 16-Mbit (1M words × 16-bit) Static RAM with Error-Correcting Code (ECC) Document Number: 001-81540						
Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change			
*P	4791835	NILE	06/09/2015	Changed status from Preliminary to Final.			
*Q	5436639	NILE	09/14/2016	Updated Maximum Ratings: Updated Note 9 (Replaced "2 ns" with "20 ns"). Updated DC Electrical Characteristics: Removed Operating Range "2.7 V to 3.6 V" and all values corresponding to V _{OH} parameter. Included Operating Ranges "2.7 V to 3.0 V" and "3.0 V to 3.6 V" and all values corresponding to V _{OH} parameter. Changed minimum value of V _{IH} parameter from 2.2 V to 2 V corresponding to Operating Range "4.5 V to 5.5 V". Updated Ordering Information: Updated part numbers. Updated to new template.			
*R	5580947	NILE	01/10/2017	Updated Logic Block Diagram – CY7C1061G. Updated Package Diagrams: spec 51-85183 – Changed revision from *D to *F. Updated to new template.			
*S	5775815	AESATMP9	06/16/2017	Updated logo and copyright.			
*T	6245720	NILE	07/13/2018	Updated Features: Added Note 2 and referred the same note in "Embedded error-correcting code (ECC) for single-bit error correction". Updated to new template. Completing Sunset Review.			



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